

Semiconductor devices - Mechanical and climatic test methods - Part 39: Measurement of moisture diffusivity and water solubility in organic materials used for semiconductor components

EESTI STANDARDI EESSÕNA

NATIONAL FOREWORD

See Eesti standard EVS-EN IEC 60749-39:2022 sisaldab Euroopa standardi EN IEC 60749-39:2022 ingliskeelset teksti.	This Estonian standard EVS-EN IEC 60749-39:2022 consists of the English text of the European standard EN IEC 60749-39:2022.
Standard on jõustunud sellekohase teate avaldamisega EVS Teatajas	This standard has been endorsed with a notification published in the official bulletin of the Estonian Centre for Standardisation and Accreditation.
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English Version

**Semiconductor devices - Mechanical and climatic test methods -
Part 39: Measurement of moisture diffusivity and water solubility
in organic materials used for semiconductor components
(IEC 60749-39:2021)**

Dispositifs à semiconducteurs - Méthodes d'essais
mécaniques et climatiques - Partie 39: Mesure de la
diffusivité d'humidité et de l'hydrosolubilité dans les
matériaux organiques utilisés dans les composants à
semiconducteurs
(IEC 60749-39:2021)

Halbleiterbauelemente - Mechanische und klimatische
Prüfverfahren - Teil 39: Messung des
Feuchtediffusionskoeffizienten und der Wasserlöslichkeit in
organischen Werkstoffen, welche bei Halbleiter-
Komponenten verwendet werden
(IEC 60749-39:2021)

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Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Rue de la Science 23, B-1040 Brussels

European foreword

The text of document 47/2652/CDV, future edition 2 of IEC 60749-39, prepared by IEC/TC 47 "Semiconductor devices" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN IEC 60749-39:2022.

The following dates are fixed:

- latest date by which the document has to be implemented at national (dop) 2022-10-03 level by publication of an identical national standard or by endorsement
- latest date by which the national standards conflicting with the (dow) 2025-01-03 document have to be withdrawn

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Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 Where an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60749-20	-	Semiconductor devices - Mechanical and climatic test methods - Part 20: Resistance of plastic encapsulated SMDs to the combined effect of moisture and soldering heat	EN IEC 60749-20	-

INTERNATIONAL STANDARD

NORME INTERNATIONALE

**Semiconductor devices – Mechanical and climatic test methods –
Part 39: Measurement of moisture diffusivity and water solubility in organic
materials used for semiconductor components**

**Dispositifs à semiconducteurs – Méthodes d'essais mécaniques et
climatiques –
Partie 39: Mesure de la diffusivité d'humidité et de l'hydrosolubilité dans les
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INTERNATIONAL ELECTROTECHNICAL COMMISSION

**SEMICONDUCTOR DEVICES –
MECHANICAL AND CLIMATIC TEST METHODS –****Part 39: Measurement of moisture diffusivity and water solubility in
organic materials used for semiconductor components**

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This edition includes the following significant technical changes with respect to the previous edition:

- a) updated procedure for "dry weight" determination.

The text of this International Standard is based on the following documents:

Draft	Report on voting
47/2652/CDV	47/2725/RVC

Full information on the voting for its approval can be found in the report on voting indicated in the above table.

The language used for the development of this International Standard is English.

This document was drafted in accordance with ISO/IEC Directives, Part 2, and developed in accordance with ISO/IEC Directives, Part 1 and ISO/IEC Directives, IEC Supplement, available at www.iec.ch/members_experts/refdocs. The main document types developed by IEC are described in greater detail at www.iec.ch/standardsdev/publications.

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